


<b>Search Notes</b> 	<b>Application/Control No.</b>		<b>Applicant(s)/Patent under Reexamination</b>	
	10/608,761		WIEROWSKI, JAMES V.	
	<b>Examiner</b>		<b>Art Unit</b>	
	Le Nguyen		2174	

SEARCHED			
Class	Subclass	Date	Examiner
715	712	3/10/2007	LVN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
US-PGPub, USPAT: 715/712		3/10/2007	LVN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
inventor name search	3/10/2007	LVN
US-PGPub, USPAT: 715/712,734,738,739,805,838,850- 855,513; 701/201,208,210; 705/26,27	3/10/2007	LVN
consulted w/Ba Huynh	3/11/2007	LVN
consulted w/Ba Huynh	3/15/2007	LVN